

Abstract Submitted  
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**Characterization of Stock Blu-ray diodes** MARK CUNNINGHAM, JAMES ARCHIBALD, CHRISTOPHER ERICKSON, DALLIN DURFEE, Brigham Young University — I am developing a process to test and characterize diodes of unknown wavelengths. using a B&WTEK Spectrometer we are characterizing the wavelength of 405 nm blu-ray diodes purchased in bulk. With the known error in production of the Diode Lasers we are hoping to find a diode at 408 nm to use in driving a raman transition between hyperfine states of strontium 87 ions. The bulk of the project is a java program that communicates with the spectrometer and graphically displays the intensities of the wavelengths from the laser diodes.

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